

PATENT 0459-0649P

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant:

BOGGILD, Peter

Conf.:

1235

Appl. No.:

09/938,153

Group:

UNASSIGNED

Filed:

August 24, 2001

Examiner: UNASSIGNED

For:

FABRICATION AND APPLICATION OF NANO-MANIPULATORS WITH FOCUSED BEAM INDUCED

GROWTH

INFORMATION DISCLOSURE STATEMENT (SUBMISSION AFTER FILING OF AN APPLICATION BUT BEFORE FINAL REJECTION OR NOTICE OF ALLOWANCE OR CONCURRENTLY WITH A RULE 53(d) CPA APPLICATION OR WITH A RULE 1.114 RCE APPLICATION)

Assistant Commissioner for Patents Washington, DC 20231

February 19,

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION I.

The patents, publications, or other information submitted for consideration by the Office are listed on the PTO-1449(s), attached hereto.

COPIES (check at least one box) II.

- Submitted herewith is a legible copy of (i) each a. U.S. and foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- Some or all of the documents listed on the PTOb. 1449 are not enclosed because they were cited in the International Search Report and copies should already be in the PTO file. If copies are needed, please contact the undersigned.

III. CONCISE EXPLANATION OF THE RELEVANCE (check at least one box)

a. DOCUMENTS IN THE ENGLISH LANGUAGE

The attached patents, publications, or other information in the English language do not require a statement of relevancy.

b. DOCUMENTS NOT IN THE ENGLISH LANGUAGE

A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:

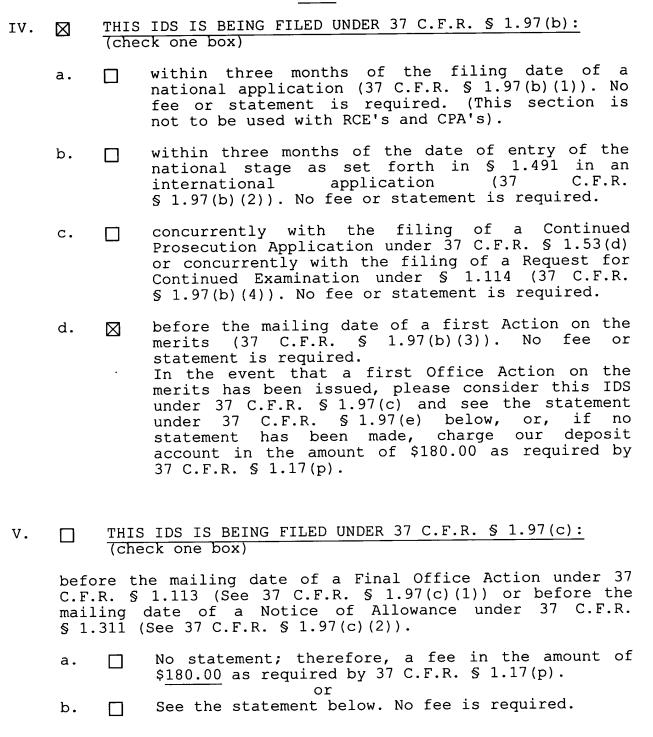
An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).

d. OTHER

The following additional information is provided for the Examiner's consideration.

"High Resolution Electron Beam Induced Deposition" to Koops et al. and "Focused Ion-Beam Technology and Applications" to Melngalis are discussed on page 5 of the present application, and "The Formation of a Connection between Carbon Nanotubes in an Electron Beam" to Banhard is discussed on page 20.

FEES



VI.	STATEMENT UNDER 37 C.F.R. § 1.97(e) (check only one box)								
	The undersigned hereby states that								
	a.		each item of information contained in the IDS was first cited in any communication from a foreign Patent Office in a counterpart foreign application not more than three months prior to the filing of this IDS; or						
	b.		no item of information contained in the IDS was cited in a communication from a foreign Patent Office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of IDS was known to any individual designated in 37 C.F.R. § 1.56(c) more than three months prior to the filing of the IDS.						
	c.		Some of the items of information were cited in a communication from a foreign Patent Office. As to this information, the undersigned states that each item of information contained in the IDS was cited in a communication from a foreign Patent Office in a counterpart foreign application not more than three months prior to the filing of this IDS. As to the remaining information, the undersigned hereby states that no item of this remaining information contained in the IDS was cited in a communication from a foreign Patent Office in a counterpart foreign application and, to the best of my knowledge after making reasonable inquiry, was known to any individual designated in 37 C.F.R. § 1.56(c) more than three months prior to the filing of this statement.						
VII.	PAYMENT OF FEES (check one box)								
		A check in the amount of \$180.00 as required by C.F.R. § 1.17(p) is enclosed for the above-identified.							
		Please charge Deposit Account No. 02-2448 in the amount required by 37 C.F.R. § 1.17(p) for the above indicated fee. A triplicate copy of this paper is attached.							
	\boxtimes	No fe	ee is required.						

If the Examiner has any questions concerning this IDS, he/she is requested to contact the undersigned. If it is determined that this IDS has been filed under the wrong rule, the PTO is requested to consider this IDS under the proper rule and charge the appropriate fee to Deposit Account No. 02-2448.

If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies, to charge payment or credit any overpayment to Deposit Account No. 02-2448 for any additional fees required under 37 C.F.R. § 1.16 or under § 1.17; particularly, extension of time fees.

Respectfully submitted,

BIRCH, STEWART, KOLASCH & BIRCH, LLP

Joe McKinney Muncy, #32,334

P.O. Box 747 \
Falls Church, VA 22040-0747 (703) 205-8000

KM/as 0459-0649P

Enclosures:

□ Documents

Foreign Search Report

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□ Other:

(Rev. 10/31/01

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		U.S. PATENT D	OCUMENTS					
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journal, seri	rar, symposium, cacarog, etc., data, page(s),	volume-issue number(s), publ	lisher, city and/or country where	published.				
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EXAMINER			DATE CONSIDERED					
EXAMINER: Ini	itial if citation considered, whether or not ci Include copy of this form with next communicat	itation is in conformance wi	th M.P.E.P. 609; Draw line throu	gh citation	if not in co	nformance and	not	